

**Corrections to "Scattering Parameter Characterization of Microwave Optoelectronic Devices and Fiber-Optic Networks"**

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In the above letter,<sup>1</sup> p. 234 contains three errors. At the end of the first column, the element in the first column and second row of  $R_{T_{\text{dut}}}$  should read:

$$-(kr)^{-1}S'T'_1 + (pr)^{-1}T'_3.$$

<sup>1</sup> S. Iezekiel, C. M. Snowden, and M. J. Howes, *IEEE Microwave Guided Wave Lett.*, vol. 1, no. 9, pp. 233-235, Sept. 1991.

Manuscript received October 1, 1991.

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IEEE Log Number 9104591.

The expression for  $S'$  in the second column should read:

$$S' = \frac{S_{22\text{E/O}}}{S_{12,\text{E/O}}S_{21,\text{E/O}}}.$$

The expression given for  $ks/pr$ , in the second column, was inadvertently taken from the optical calibration theory. The correct expression for the optoelectronic calibration is:

$$\frac{ks}{pr} = \frac{-R_{11,\text{M3}} + \bar{c}R_{12,\text{M3}} + \bar{b}R_{21,\text{M3}} - \bar{b}\bar{c}R_{22,\text{M3}}}{R_{11,\text{M3}} - \bar{d}R_{12,\text{M3}} - \bar{a}R_{21,\text{M3}} + \bar{a}\bar{d}R_{22,\text{M3}}} \frac{1}{S_{12,\text{E/O}}S_{21,\text{E/O}}},$$

where  $R_{ij,\text{M3}}$  are the measured elements of the wave cascading matrix of **E03** and  $S_{ij,\text{E/O}}$  are the actual  $S$ -parameters of the network **E/O**. It has also come to light that the sign ambiguity in the values of  $ks$  and  $pr$  can be resolved by measuring the optical standard **O3** with the calibrated optical network analyzer set-up. No estimate of the phase of  $S_{11,\text{EO3}}$  is required. Hence, the optoelectronic calibration procedure is actually more robust than originally thought. The rest of the letter was not affected by these errors.